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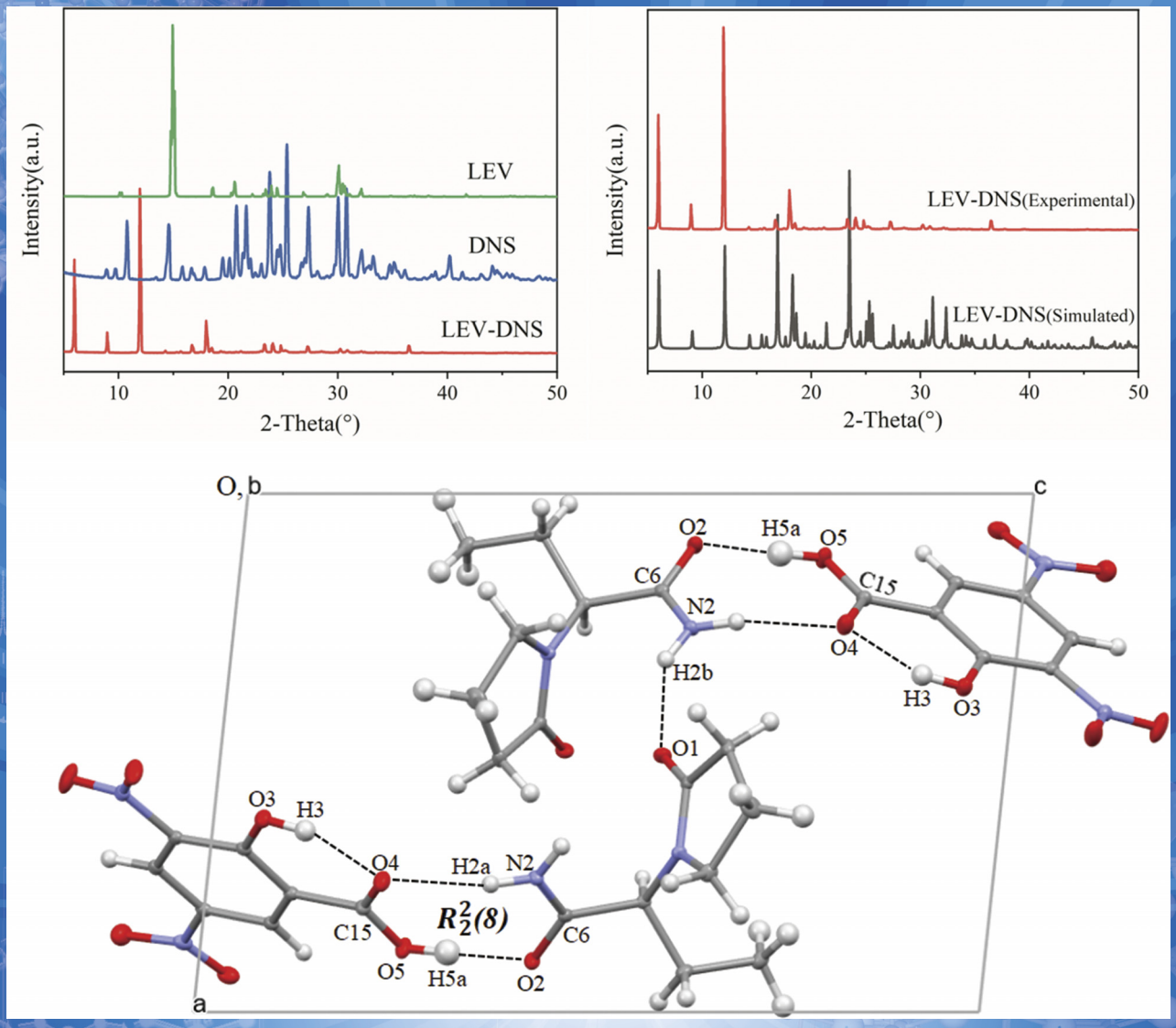

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Aims & Scope
ICDD's quarterly, and special topical issue, international journal, *Powder Diffraction*, focuses on materials characterization employing X-ray powder diffraction and related techniques. With feature articles covering a wide range of applications, from mineral analysis to epitactic growth of thin films to advances in application software and hardware, this journal offers a wide range of practical applications. ICDD, in collaboration with the Denver X-ray Conference Organizing Committee, has increased services for the subscribers of Powder Diffraction and authors of Advances in X-ray Analysis. Beginning in 2006, ICDD offered a copy of the previous year's edition of AXA to Powder Diffraction institutional subscribers who receive both print and on-line versions. This effectively doubles the number of articles annually available to Powder Diffraction subscribers and significantly increases the circulation for the authors in Advances in X-ray Analysis.

Subject coverage includes:
- Techniques and procedures in X-ray powder diffractometry
- Advances in instrumentation
- Study of materials including organic materials, minerals, metals and thin film superconductors
- Publication of powder data on new materials

International Centre for Diffraction Data
The International Centre for Diffraction Data (ICDD®) is a non-profit scientific organization dedicated to collecting, editing, publishing, and distributing powder diffraction data for the identification of materials. The membership of the ICDD consists of worldwide representation from academe, government, and industry.

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On the Cover: The cover figure was prepared using figures from the manuscript "Synthesis, powder diffraction pattern, crystal structure determination of the pharmaceutical co-crystal of Levetiracetam and 3,5-dinitrosalicylic acid" by Lingling Shi, Zhejiang Sci-Tech University, Hangzhou, China and coauthors.

The upper left figures shows that the co-crystal is distinctly different from either of the constituent components. The upper right shows shows the experimental and simulated patterns of the co-crystal. The lower figure shows the derived molecular structure of the LEV-DNS co-crystal that was characterized by infrared spectroscopy, powder X-ray diffraction and single-crystal X-ray diffraction.

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